

EMC Test Report

Report No.: AGC05443220819EE01

PRODUCT DESIGNATION: keying with 3 in 1 cable

BRAND NAME : N/A

MODEL NAME : MO6820

APPLICANT: MID OCEAN BRANDS B.V

DATE OF ISSUE : Sep. 05, 2022

EN 55032:2015/A11:2020

STANDARD(S) : EN IEC 61000-3-2:2019

EN 61000-3-3:2013/A1:2019

EN 55035:2017/A11:2020

REPORT VERSION: V1.0

Attestation of Global Comphance (Shenzhen) Co., Ltd





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REPORT REVISE RECORD

Report Version	Revise Time	Issued Date	Valid Version	Notes
V1.0	/	Sep. 05, 2022	Valid	Initial release

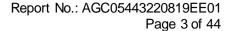
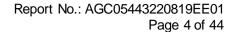




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1 VERIFICATION OF CONFORMITY

Applicant	MID OCEAN BRANDS B.V
Address	7/F, Kings Tower, 111 King Lam Street, Cheung Sha Wan, Kowloon, Hong Kong
Manufacturer	MID OCEAN BRANDS B.V
Address	7/F, Kings Tower, 111 King Lam Street, Cheung Sha Wan, Kowloon, Hong Kong
Factory	MID OCEAN BRANDS B.V
Address	7/F, Kings Tower, 111 King Lam Street, Cheung Sha Wan, Kowloon, Hong Kong
Product Designation	keying with 3 in 1 cable
Brand Name	N/A
Test Model	MO6820
Date of test	Aug. 29, 2022 to Sep. 05, 2022
Deviation	No deviation from the test method.
Condition of Test Sample	Normal
Test Result	Pass

The above equipment was tested by Attestation of Global Compliance (Shenzhen) Co., Ltd. for compliance with the requirements set forth in the Technical Standards mentioned above. This said equipment in the configuration described in this report shows the maximum emission levels emanating from equipment and the level of the immunity endurance of the equipment are within the compliance requirements.

The test results of this report relate only to the tested sample identified in this report.

Prepared By	Jouk Gai	
	Jack Gui (Project Engineer)	Sep. 05, 2022
Reviewed By	Calin Lin	
	Calvin Liu (Reviewer)	Sep. 05, 2022
Approved By	Formest 12	
	Forrest Lei (Authorized Officer)	Sep. 05, 2022

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2 SYSTEM DESCRIPTION

	TEST MODE DESCRIPTION					
NO.	NO. TEST MODE DESCRIPTION WORST					
1	Charging mode	V				
Note: 1. V m	Note: 1. V means EMI worst mode.					

3 MEASUREMENT UNCERTAINTY

The uncertainty is calculated using the methods suggested in the "Guide to the Expression of Uncertainty in measurement" (GUM) published by ISO.

- Uncertainty of Conducted Emission, Uc = ±2.9dB
- Uncertainty of Radiated Emission, Uc = ±3.8 dB



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4 PRODUCT INFORMATION

Housing Type	Plastic and metal
EUT Input Rating	DC 5.0V by adapter
EUT Output Rating	DC 5.0V 1.0A
Hardware Version	N/A
Software Version	N/A

I/O Port Information (⊠Applicable ☐ Not Applicable)

I/O Port of EUT						
I/O Port Type Number Cable Description Tested With						
USB port	1		1			
Type-C port	2		2			
Lightning port	1		1			



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5 SUPPORT EQUIPMENT

Device Type	Manufacturer	Model Name	Serial No.	Data Cable	Power Cable
Smartphone	Xiaomi	Mi 10			1.0m unshielded
Adapter	Jinbaotong	K-T10E0502000E			

Note: All the above equipment/cables were placed in worse case positions to maximize emission signals during emission test.



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6 TEST FACILITY

Site	Attestation of Global Compliance (Shenzhen) Co., Ltd
Location	1-2/F, Building 19, Junfeng Industrial Park, Chongqing Road, Heping Community, Fuhai Street, Bao 'an District, Shenzhen, Guangdong, China

7 TEST EQUIPMENT LIST

TEST EQUIPMENT OF CONDUCTED EMISSION TEST

Equipment	Manufacturer	Model	S/N	Cal. Date	Cal. Due
Test Receiver	R&S	ESPI	101206	Mar. 28, 2022	Mar. 27, 2023
Artificial power network	R&S	ESH2-Z5	100086	Jun. 08, 2022	Jun. 07, 2023
Test software	R&S	ES-K1(Ver.V1.7.1)	N/A	N/A	N/A

TEST EQUIPMENT OF RADIATED EMISSION TEST

Equipment	Manufacturer	Model	S/N	Cal. Date	Cal. Due
Test Receiver	R&S	ESCI	10096	Mar. 28, 2022	Mar. 27, 2023
Antenna	SCHWARZBECK	VULB9168	494	Jan. 08, 2021	Jan. 07, 2023
Test software	FARA	EZ-EMC (Ver.RA-03A)	N/A	N/A	N/A

TEST EQUIPMENT OF POWER HARMONICS/VOLTAGE FLUCTUATION/FLICKER

Equipment	Manufacturer	Model	S/N	Cal. Date	Cal. Due
Signal Conditioning Unit	Schaffner	CCN1000-1	72431	Jul. 06, 2022	Jul. 05, 2023
AC Source	Schaffner	NSG1007	56825	Jun. 08, 2022	Jun. 07, 2023

TEST EQUIPMENT OF SURGE/EFT/DIPSTEST

Description	Manufacturer	Model	S/N	Cal. Date	Cal. Due
EFT Surge Generator	Schaffner	Modula 6150	34437	Jun. 23, 2021	Jun. 22, 2023

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TEST EQUIPMENT OF ESD TEST

Equipment	Manufacturer	Model	S/N	Cal. Date	Cal. Due
ESD Simulator	Schaffner	NSG 438	782	Jan. 03, 2022	Jan. 02, 2023

TEST EQUIPMENT OF RS IMMUNITY TEST

Equipment	Manufacturer	Model	S/N	Cal. Date	Cal. Due
Signal Generator	R&S	E4421B	MY43351603	Mar. 04, 2022	Mar. 03, 2023
Power Sensor	R&S	URV5-Z4	100124	Apr. 26, 2021	Apr. 25, 2023
Power Meter	R&S	NRVD	8323781027 Apr. 26, 2021 Apr		Apr. 25, 2023
Power Amplifier	KALMUS	7100LC	04-02/17-06-001	N/A	N/A
Power Amplifier	Milmega	AS0104-55_55	1004793	N/A	N/A
Double-Ridged Waveguide Horn	ETS LINDGREN	3117	00034609	Apr. 23, 2021	Apr. 22, 2023
Antenna	ETS	3142C	00060447	N/A	N/A
Power Amplifier	rflight	NTWPA-256010 0	17063183	N/A	N/A
Broadband High Gain Horn Antenna	SCHWARZBEC K	BBHA 9120 J	00073	N/A	N/A

TEST EQUIPMENT OF CS IMMUNITY TEST

Description	Manufacturer	Model	S/N	Cal. Date	Cal. Due
Power Amplifier	AR	75A250	18464	N/A	N/A
CDN	ZHINAN	ZN3751	15004	Aug. 03, 2022	Aug. 02, 2024
6dB attenuator	ZHINAN	E-002	N/A	Aug. 04, 2022	Aug. 03, 2024
Power Sensor	R&S	URV5-Z4	100124	Apr. 26, 2021	Apr. 25, 2023
Power Meter	R&S	NRVD	8323781027	Apr. 26, 2021	Apr. 25, 2023
Signal Generator	R&S	E4421B	MY43351603	Mar. 04, 2022	Mar. 03, 2023

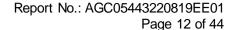


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8 TESTSUMMARY LIST

Test item	Test Requirement	Test Method	Class/Severity	Result
Conducted emission	EN 55032	EN 55032	Class B	Pass
Radiated emission	EN 55032	EN 55032	Class B	Pass
Harmonic current emission	EN IEC 61000-3-2	EN IEC 61000-3-2	Class A	N/A
Voltage fluctuations & flicker	EN 61000-3-3	EN 61000-3-3	§5 of EN 61000-3-3	Pass
Electrostatic discharge immunity	EN 55035	EN 61000-4-2	± 8.0 kV (Air Discharge) ± 4.0 kV (Contact Discharge) ± 4.0 kV (Indirect Discharge)	Pass
Radiated electromagnetic field immunity	EN 55035	EN 61000-4-3	3V/m with 80% AM. 1kHz Modulation.	Pass
Electrical fast transient/burst Immunity	EN 55035	EN 61000-4-4	+/- 1kV for Power Supply Lines	Pass
Surge immunity	EN 55035	EN 61000-4-5	+/- 1kV (Line to Line)	Pass
Immunity to Conducted Disturbances Induced by RF fields	EN 55035	EN 61000-4-6	3V(0.15MHz-10MHz) 3V-1V(10MHz-30MHz) 1V(30MHz-80MHz) with 80% AM. 1 kHz Modulation	Pass
Power frequency magnetic field	EN 55035	EN 61000-4-8	1A/m 50Hz or 60Hz	N/A
Voltage dips and short interruptions immunity	EN 55035	EN 61000-4-11	Odegrees	Pass

Note: N/Ameans not applicable.





9 EN 55032 LINE CONDUCTED EMISSION TEST

9.1 LIMITS OF LINE CONDUCTED EMISSION TEST

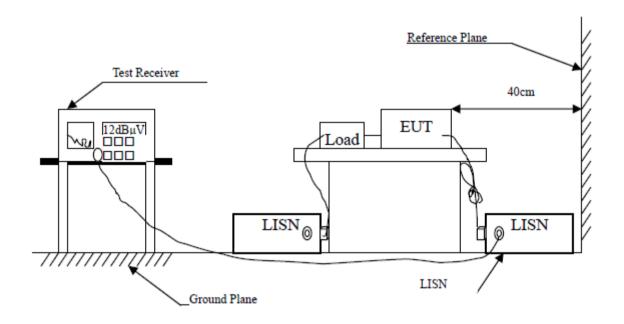
AT AC MAINS POWER PORT

Fraguanay	Maximum RF Line Voltage				
Frequency	Q.P.(dBuV)	Average(dBuV)			
150kHz-500kHz	66-56	56-46			
500kHz-5MHz	56	46			
5MHz-30MHz	60	50			

Note:

- 1. The lower limit shall apply at the transition frequency.
- 2. The limit decreases linearly with the logarithm of the frequency in the range 0.15 MHz to 0.50MHz.

9.2 BLOCK DIAGRAM OF TEST SETUP





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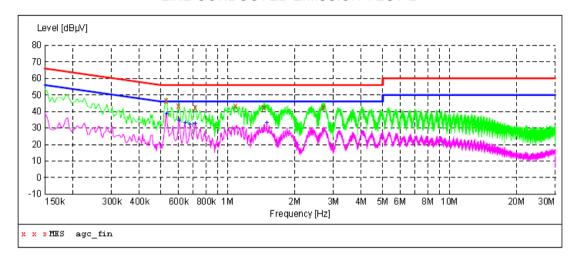
9.3 PROCEDURE OF LINE CONDUCTED EMISSION TEST

- (1)The equipment was set up as per the test configuration to simulate typical actual usage per the user's manual. When the EUT is a tabletop system, a wooden table with a height of 0.8 meters is used and is placed on the ground plane as per EN55032 (see Test Facility for the dimensions of the ground plane used). When the EUT is a floor-standing equipment, it is placed on the ground plane which has a 10cm non-conductive covering to insulate the EUT from the ground plane.
- (2) Support equipment, if needed, was placed as per EN55032.
- (3) All I/O cables were positioned to simulate typical actual usage as per EN55032.
- (4) The EUT received AC 230V 50Hz power through a Line Impedance Stabilization Network (LISN) which supplied power source and was grounded to the ground plane.
- (5) All support equipments received power from a second LISN supplying power of AC230V and 110V/50Hz, if any.
- (6) The EUT test program was started. Emissions were measured on each current carrying line of the EUT using a spectrum Analyzer / Receiver connected to the LISN powering the EUT. The LISN has two monitoring points: Line 1 (Hot Side) and Line 2 (Neutral Side). Two scans were taken: one with Line 1 connected to Analyzer / Receiver and Line 2 connected to a 50 ohm load; the second scan had Line 1 connected to a 50 ohm load and Line 2 connected to the Analyzer / Receiver.
- (7) Analyzer / Receiver scanned from 150kHz to 30MHz for emissions in each of the test modes.
- (8) During the above scans, the emissions were maximized by cable manipulation.
- (9) A scan was taken on both power lines, Line 1 and Line 2, recording at least the six highest emissions.
- (10) Emission frequency and amplitude were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit. If EUT emission level was less –2dB to the A.V. limit in Peak mode, then the emission signal was re-checked using Q.P and Average detector.



9.4 TEST RESULT OF LINE CONDUCTED EMISSION TEST

LINE CONDUCTED EMISSION TEST-L



MEASUREMENT RESULT: "agc fin"

Frequency MHz	Level dBµV	Transd dB	Limit dBµV	Margin dB	Detector	Line
0.530000	46.60	5.4	56	9.4	QP	L1
0.602000	43.30	5.4	56	12.7	QP	L1
0.714000	42.20	5.4	56	13.8	QP	L1
1.090000	43.30	5.6	56	12.7	QP	L1
1.458000	42.60	6.0	56	13.4	QP	L1
2.706000	42.30	6.5	56	13.7	QP	L1

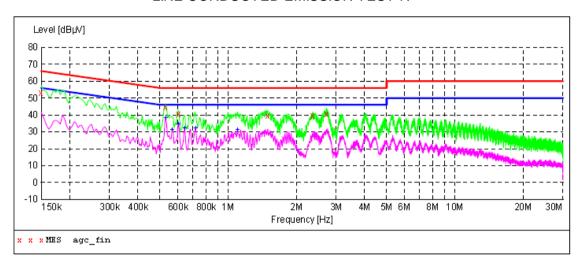
MEASUREMENT RESULT: "agc fin2"

Frequency MHz	Level dBµV	Transd dB	Limit dBµV	Margin dB	Detector	Line
0.530000	38.40	5.4	46	7.6	AV	L1
0.606000	34.40	5.4	46	11.6	AV	L1
0.642000	33.00	5.4	46	13.0	AV	L1
0.678000	32.20	5.4	46	13.8	AV	L1
0.714000	32.50	5.4	46	13.5	AV	L1
1.502000	32.80	6.0	46	13.2	AV	L1

RESULT: PASS



LINE CONDUCTED EMISSION TEST-N



MEASUREMENT RESULT: "agc_fin"

Frequency MHz	Level dBµV	Transd dB	Limit dBµV	Margin dB	Detector	Line
0.150000	53.10	6.9	66	12.9	QP	N
0.530000	44.50	5.4	56	11.5	QP	N
0.606000	40.70	5.4	56	15.3	QP	N
1.498000	39.70	6.0	56	16.3	QP	N
2.358000	39.40	6.5	56	16.6	QP	N
2.718000	40.60	6.5	56	15.4	QP	N

MEASUREMENT RESULT: "agc fin2"

Frequency MHz	Level dBµV	Transd dB	Limit dBµV	Margin dB	Detector	Line
0.530000	38.30	5.4	46	7.7	AV	N
0.566000	31.40	5.4	46	14.6	AV	N
0.606000	34.50	5.4	46	11.5	AV	N
0.642000	32.20	5.4	46	13.8	AV	N
0.718000	31.90	5.4	46	14.1	AV	N
1.102000	31.30	5.6	46	14.7	AV	N

RESULT: PASS

Note:

$$\label{eq:measurement} \begin{split} & \text{Measurement Level}(\text{dBuV}) = \text{Receiver reading}(\text{dBuV}) + \text{Tansd}(\text{dB}) \\ & \text{Transd}(\text{dB}) = \text{AMN Factor}(\text{dB}) + \text{Cable Loss}(\text{dB}) + \text{Attenuation}(\text{dB}) \text{ for Attenuator Margin} = \text{Limit-Level} \end{split}$$



10 EN 55032 RADIATED EMISSION TEST

10.1 LIMITS OF RADIATED DISTURBANCES

Limits for radiated disturbance 30M to1 GHz at a measurement distance of 3 m

Frequency range (MHz)	Quasi peak limits(dBuV/m), for Class B ITE, at 3m measurement distance
30 - 230	40
230 - 1000	47

Limits for radiated disturbance above 1 GHz at a measurement distance of 3 m

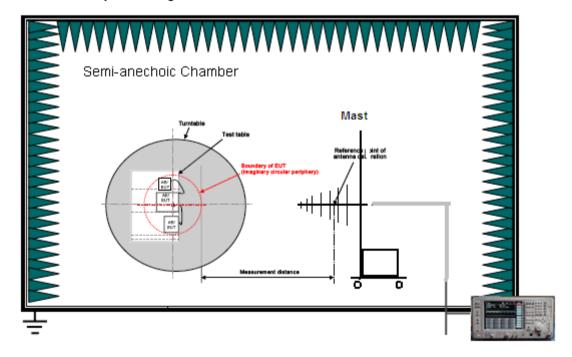
Eroguanov rango (MH=)	Limits (dBuV/m), Class B ITE			
Frequency range (MHz)	Peak	Average		
1000-3000	70	50		
3000-6000	74	54		

Notes:

- 1. The lower limit shall apply at the transition frequency.
- 2. Additional provisions may be required for cases where interference occurs.

10.2 BLOCK DIAGRAM OF TEST SETUP

System Diagram of Connections between EUT and Simulators





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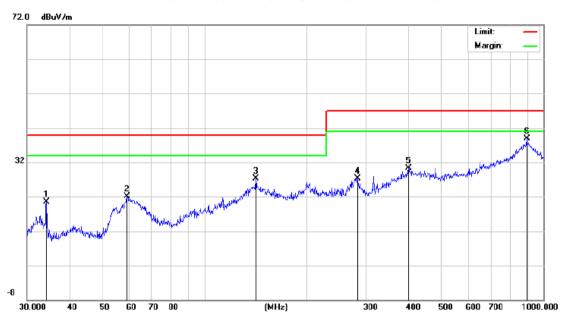
10.3 PROCEDURE OF RADIATED EMISSION TEST

- (1) The equipment was set up as per the test configuration to simulate typical actual usage per the user's manual. When the EUT is a tabletop system, a wooden turntable with a height of 0.8 meters is used which is placed on the ground plane as per EN 55032 (see Test Facility for the dimensions of the ground plane used). When the EUT is a floor-standing equipment, it is placed on the ground plane which has a 10cm non-conductive covering to insulate the EUT from the ground plane.
- (2) Support equipment, if needed, was placed as per EN 55032.
- (3) All I/O cables were positioned to simulate typical actual usage as per EN 55032.
- (4) The EUT was turned on.
- (5) The antenna was placed at 3 meter away from the EUT as stated in EN 55032. The antenna connected to the Analyzer via a cable and at times a pre-amplifier would be used.
- (6) The Analyzer / Receiver quickly scanned from 30MHz to 1000MHz. The EUT test program was started. Emissions were scanned and measured rotating the EUT to 360 degrees and positioning the antenna 1 to 4 meters above the ground plane, in both the vertical and the horizontal polarization, to maximize the emission reading level.
- (7) The test mode(s) were scanned during the test:
- (8) Recorded at least the six highest emissions. Emission frequency, amplitude, antenna position, polarization and turntable position were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit and Q.P./Peak reading is presented.



10.4 TEST RESULT OF RADIATED EMISSION TEST

Radiated Emission Test at 3m Distance-Horizontal

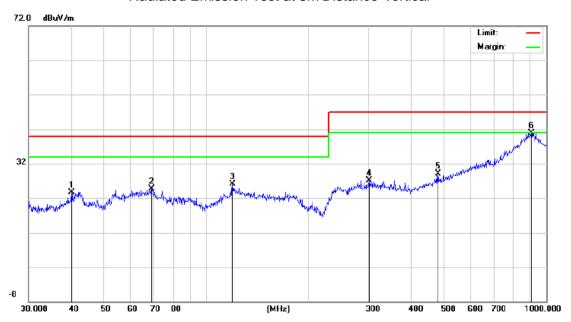


No.	Mk.	Freq.	Reading Level	Correct Factor	Measure- ment	Limit	Over	
		MHz	dBuV	dB	dBuV/m	dBuV/m	dΒ	Detector
1		34.2760	16.15	4.30	20.45	40.00	-19.55	peak
2		59.2325	6.39	15.65	22.04	40.00	-17.96	peak
3	1	41.8262	7.71	19.51	27.22	40.00	-12.78	peak
4	2	82.9852	6.02	21.27	27.29	47.00	-19.71	peak
5	4	00.4319	6.54	23.67	30.21	47.00	-16.79	peak
6	* 8	93.8567	7.39	31.60	38.99	47.00	-8.01	peak

RESULT: PASS



Radiated Emission Test at 3m Distance-Vertical



No	. Mk	. Freq.	Reading Level	Correct Factor	Measure- ment	Limit	Over	
		MHz	dBuV	dΒ	dBuV/m	dBuV/m	dΒ	Detector
1		40.1347	7.73	16.07	23.80	40.00	-16.20	peak
2		69.1141	6.54	18.09	24.63	40.00	-15.37	peak
3		119.4361	7.30	18.83	26.13	40.00	-13.87	peak
4		301.4224	6.59	20.45	27.04	47.00	-19.96	peak
5		480.5276	7.80	21.40	29.20	47.00	-17.80	peak
6	*	903.3094	6.44	34.54	40.98	47.00	-6.02	peak

RESULT: PASS

Level(dBuV/m) = Reading(dBuV) + Factor(dB/m)

Factor(dB/m)=Antenna Factor(dB/m)+Cable loss(dB)+Attenuation(dB)for Attenuator

Over= Measurement-Limit



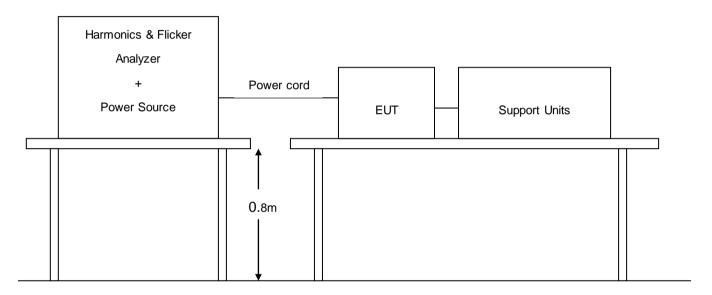
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11 EN IEC 61000-3-2 POWER HARMONICS TEST

POWER HARMONICS MEASUREMENT

Port	AC mains
Basic Standard EN IEC 61000-3-2	
Limits	⊠CLASS A ;□CLASS B; □CLASS C; □CLASS D
Temperature	25°C
Humidity	62% RH

11.1 BLOCK DIAGRAM OF TEST SETUP



11.2 RESULT

Note: Owning to the power of EUT is less than 75W, so test is not applicable.

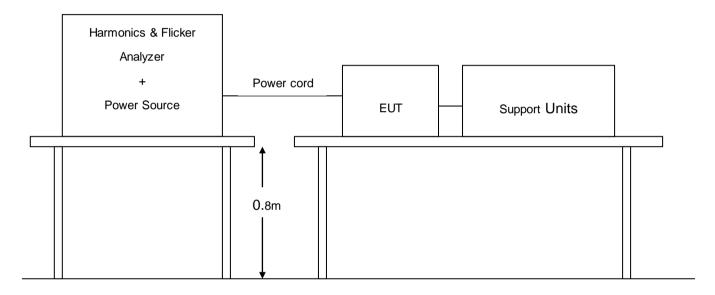


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12 EN 61000-3-3 VOLTAGE FLUCTUATION / FLICKER TEST VOLTAGE FLUCTUATION / FLICKER MEASUREMENT

Port AC mains	
Basic Standard	EN 61000-3-3
Limits §5 of EN 61000-3-3	
Temperature	26°C
Humidity	64% RH

12.1 BLOCK DIAGRAM OF TEST SETUP





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12.2 RESULT

Flicker Test Summary per EN/IEC61000-3-3 (Run time)

	3 1	'	
Test Parameter	Measurement Value	Limit	Remarks
Time(mS) > dt:	0.0	500.0	Pass
Highest dc (%):	0.00	3.30	Pass
Highest dmax (%):	0.00	4.00	Pass
Highest Pst (10 min. period):	0.248	1.0	Pass
Highest Plt (2 hr. period):	0.108	0.65	Pass



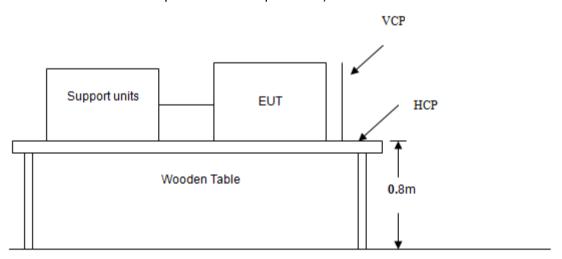
13 EN 61000-4-2 ESD IMMUNITY TEST

ELECTROSTATIC DISCHARGE (ESD) IMMUNITY TEST

Port	Enclosure		
Basic Standard	EN 61000-4-2		
Test Level	± 8.0 kV (Air Discharge) ± 4.0 kV (Contact Discharge) ± 4.0 kV (Indirect Discharge)		
Standard require	В		
Temperature	24°C		
Humidity	49% RH		

13.1 BLOCK DIAGRAM OF TEST SETUP

(The 470 k ohm resistors are installed per standard requirement)



Ground Reference Plane₽



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13.2 TEST PROCEDURE

The test procedure shall be in accordance with EN 61000-4-2. Electrostatic discharges shall be applied only to points and surfaces of the EUT which are expected to be touched during normal operation, including user access operations specified in the user manual, for example cleaning or adding consumables when the EUT is powered. The application of discharges to the contacts of open connectors is not required.

The number of test points is EUT dependent. Sub clause 8.3.1 and Clause A.5 of EN 61000-4-2 shall be taken into consideration when selecting test points, paying particular attention to keyboards, dialling pads, power switches, mice, drive slots, card slots, the areas around communication ports, etc.

When applying direct discharges to a portable or handheld battery-powered EUT with a display screen, it may not be possible to observe the screen for a given EUT orientation. If observation of the screen is necessary during this test, the EUT may be mounted vertically using non-metallic supports.

Note: As per the A2 to EN 61000-4-2, a bleed resistor cable is connected between the EUT and HCP during the test. The electrostatic discharges were applied as follows:

Voltage	Coupling	Test Performance	Result
±4kV	Contact Discharge	No function loss	А
±4kV	Indirect Discharge HCP (Front)	No function loss	А
±4kV	Indirect Discharge HCP (Left)	No function loss	А
±4kV	Indirect Discharge HCP (Back)	No function loss	А
±4kV	Indirect Discharge HCP (Right)	No function loss	А
±4kV	Indirect Discharge VCP (Front)	No function loss	А
±4kV	Indirect Discharge VCP (Left)	No function loss	А
±4kV	Indirect Discharge VCP (Back)	No function loss	А
±4kV	Indirect Discharge VCP (Right)	No function loss	А
±8kV	Air Discharge	No function loss	А

13.3 PERFURI	MANCE & RESULT
Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

⊠ PASS	□FAIL
△ <i>PA</i> 33	∟ <i>F</i> AIL

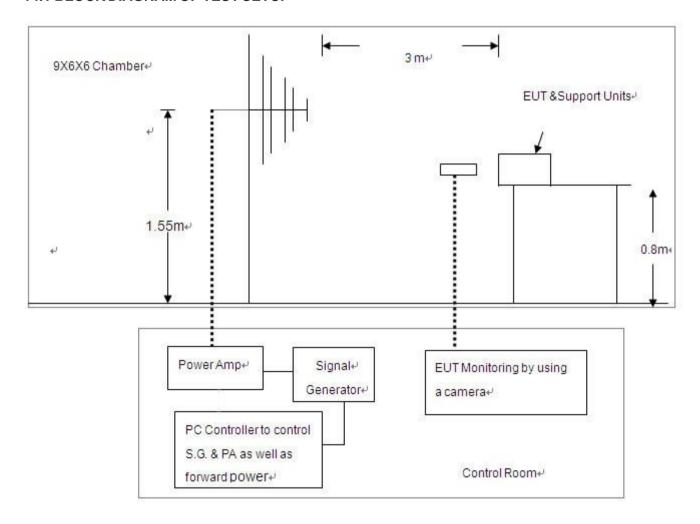


14 EN 61000-4-3 RS IMMUNITY TEST

RADIATED ELECTROMAGNETIC FIELD IMMUNITY TEST

Port Enclosure	
Basic Standard EN 61000-4-3	
Test Level: 3V/m with 80% AM. 1kHz Modulation.	
Standard require A	
Temperature	22°C
Humidity	51% RH

14.1 BLOCK DIAGRAM OF TEST SETUP





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14.2 TEST PROCEDURE

The EUT was located at the edge of supporting table keep 3 meter away from transmitting antenna, it just the calibrated square area of field uniformity. The support units were located outside of the uniformity area, but the cable(s) connected with EUT were exposed to the calibrated field as per EN 61000-4-3.

EUT worked with resistance load, and make sure EUT worked normally.

Setting the testing parameters of RS test software per EN 61000-4-3.

Performing the test at each side of with specified level (3V/m) at 1% steps and test frequency from 80MHz to 1000MHz

Recording the test result in following table.

EN 61000-4-3 Final test conditions:

Test level: 3V/m

Steps: 1 % of fundamental

Dwell Time: 1 sec

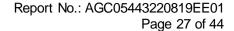
Range (MHz)	Field	Modulation	Polarity	Position	Test Performance	Result
80-1000	3V/m	AM	H/V	Front	No function loss	А
80-1000	3V/m	AM	H/V	Left	No function loss	А
80-1000	3V/m	AM	H/V	Back	No function loss	А
80-1000	3V/m	AM	H/V	Right	No function loss	А
1800,2600, 3500,5000	3V/m	AM	H/V	Front	No function loss	А
1800,2600, 3500,5000	3V/m	AM	H/V	Left	No function loss	Α
1800,2600, 3500,5000	3V/m	AM	H/V	Back	No function loss	А
1800,2600, 3500,5000	3V/m	AM	H/V	Right	No function loss	Α

Frequency (±1 %) for Spot test.

14.3 PERFORMANCE & RESULT

Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

⊠PASS	□FAIL	



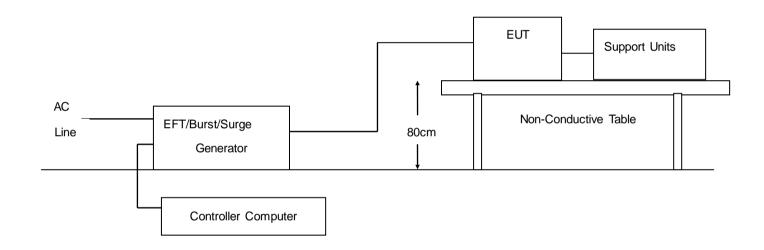


15 EN 61000-4-4 EFT IMMUNITY TEST

ELECTRICAL FAST TRANSIENTS/BURST IMMUNITY TEST

Port	On Power Supply Lines
Basic Standard	EN 61000-4-4
Test Level	+/- 1kV for Power Supply Lines
Standard require	В
Temperature	24°C
Humidity	47% RH

15.1 BLOCK DIAGRAM OF TEST SETUP





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15.2 TEST PROCEDURE

The EUT and support units were located on a wooden table 0.8m away from ground reference plane.

A 1.0 meter long power cord was attached to EUT during the test.

The length of communication cable between communication port and clamp was keeping within 1 meter.

EUT worked with resistance load, and make sure EUT worked normally.

Related peripherals work during the test.

Recording the test result as shown in following table.

Test conditions:

Impulse Frequency: 5kHz

Tr/Th: 5/50ns

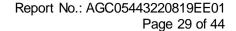
Burst Duration: 15ms Burst Period: 300ms

Inject Line	Voltage kV	Inject Method	Test Performance	Result
L+N	+/- 1	Direct	No function loss	Α

15.3 PERFORMANCE & RESULT

Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

⊠ P A	ASS □ FAIL	



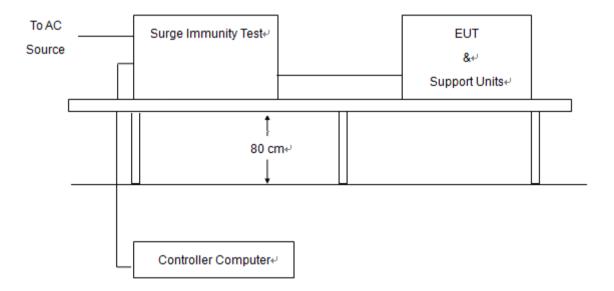


16 EN 61000-4-5 SURGE IMMUNITY TEST

SURGE IMMUNITY TEST

Port	On Power Supply Lines
Basic Standard	EN 61000-4-5
Requirements	+/- 1kV (Line to Line)
Standard require	В
Temperature	24°C
Humidity	47% RH

16.1 BLOCK DIAGRAM OF TEST SETUP





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16.2 TEST PROCEDURE

The EUT and support units were located on a wooden table 0.8 m away from ground floor.

EUT worked with resistance load, and make sure EUT worked normally.

Recording the test result as shown in following table.

Test conditions:

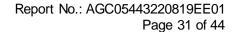
10010011111101	
Voltage Waveform	1.2/50 <i>u</i> s
Current Waveform	8/20 <i>u</i> s
Polarity	Positive/Negative
Phase angle	90°,270°
Number of Test	5

Coupling Line	Voltage (kV)	Polarity	Coupling Method	Test Performance	Result
L1-N	1	Positive	Capacitive	No function loss	А
L1-N	1	Negative	Capacitive	No function loss	Α

16.3 PERFORMANCE & RESULT

Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

⊠PASS	□FAIL
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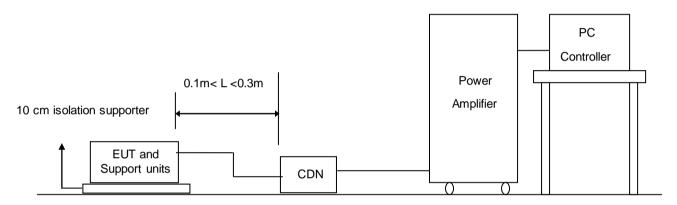




17 EN 61000-4-6 CS IMMUNITY TEST

Port	On Power Supply Lines
Basic Standard	EN 61000-4-6
Requirements	3V(0.15MHz-10MHz) 3V-1V(10MHz-30MHz) 1V(30MHz-80MHz) with 80% AM. 1 kHz Modulation
Standard require	A
Temperature	24°C
Humidity	49% RH

17.1 BLOCK DIAGRAM OF TEST SETUP



Ground Reference Plane



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17.2 TEST PROCEDURE

The EUT and support units were located at a ground reference plane with the interposition of a 0.1 m thickness insulating support and the CDN was located on GRP directly.

EUT worked with resistance load, and make sure EUT worked normally.

Related peripherals work during the test.

Setting the testing parameters of CS test software per EN 61000-4-6.

Recording the test result in following table.

Test conditions:

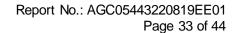
Frequency Range	0.15MHz-80MHz
Frequency Step	1% of fundamental
Dwell Time	3 sec

Range (MHz)	Strength	Modulation	Result
0.15-10	3V	АМ	Α
10-30	3V-1V	AM	A
30-80	1V	AM	Α

17.3 PERFORMANCE & RESULT

Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

⊠ <i>PASS</i> □





18 EN 61000-4-11 DIPS IMMUNITY TEST

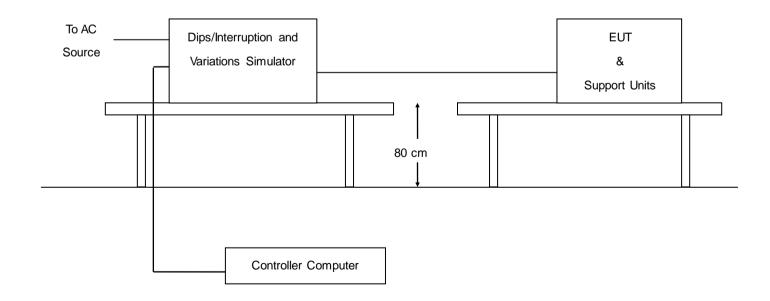
VOLTAGE DIPS. SHORT INTERRUPTIONS AND VOLTAGE VARIATIONS IMMUNITY TEST

1021/1023110	, on or in the roll and to the transfer of the initial transfer of the roll and the
Port	On Power Supply Lines
Basic Standard	EN 61000-4-11
Requirements	0degrees
Test Interval	Min. 10 sec.
Temperature	24°C
Humidity	47% RH

	Test Level % U _T	Reduction (%)	Duration (periods)	Performance Criteria
Voltage Dips	<5	>95	0.5	В
	70	30	25	С

Voltage	Test Level	Reduction	Duration	Performance
	% U _T	(%)	(periods)	Criteria
Interruptions	<5	>95	250	С

18.1 BLOCK DIAGRAM OF TEST SETUP



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18.2 TEST PROCEDURE

The EUT and support units were located on a wooden table, 0.8 m away from ground floor.

EUT worked with resistance load, and make sure EUT worked normally.

Setting the parameter of tests and then perform the test software of test simulator.

Conditions changes to occur at 0 degree crossover point of the voltage waveform.

Recording the test result in test record form.

Test conditions:

The duration with a sequence of three dips/interruptions with interval of 10 s minimum (Between each test event)

Voltage Dips:

Test Level % U _T	Reduction (%)	Duration (periods)	Observation	Performance Result
<5	>95	0.5	Normal	Α
70	30	25	Normal	Α

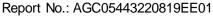
Voltage Interruptions:

Test Level % U _T	Reduction (%)	Duration (periods)	Observation	Performance Result
<5	>95	250	EUT stops charging Manual operation is required to resume normal work.	С

18.3 INTERPRETATION

Criteria A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
Criteria B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
Criteria C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

		⊠PASS
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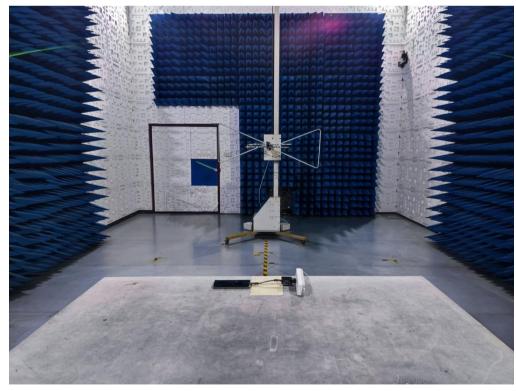
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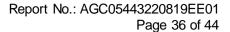
APPENDIX A: PHOTOGRAPHS OF TEST SETUP

EN 55032 CONDUCTED EMISSION TEST SETUP



EN 55032 RADIATED EMISSION TEST SETUP





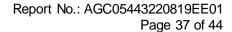


EN 61000-3-3 VOLTAGE FLUCTUATION / FLICKER TEST SETUP



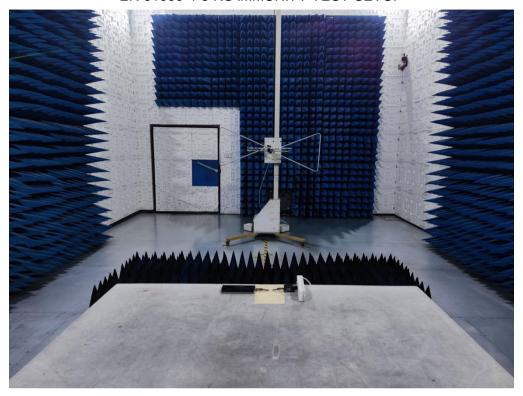
EN 61000-4-2 ESD IMMUNITY TEST SETUP



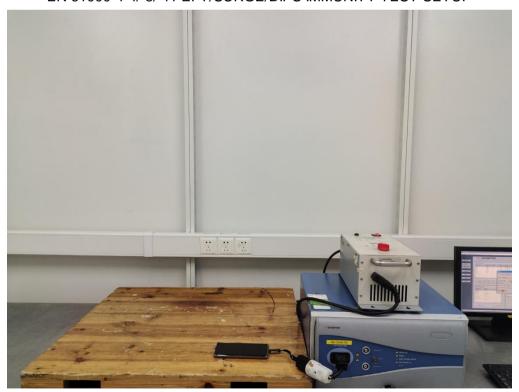


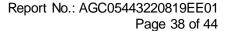


EN 61000-4-3 RS IMMUNITY TEST SETUP



EN 61000-4-4/-5/-11 EFT/SURGE/DIPS IMMUNITY TEST SETUP

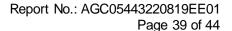








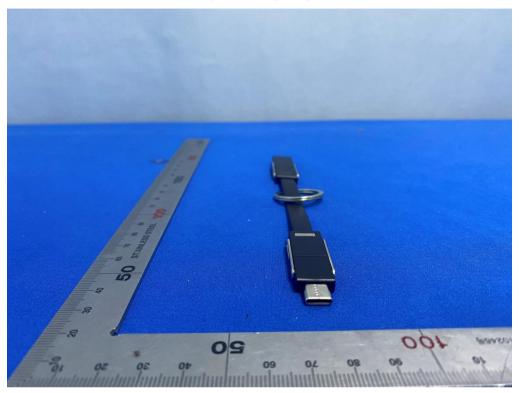






APPENDIX B: PHOTOGRAPHS OF EUT

TOP VIEW OF EUT



BOTTOW VIEW OF EUT



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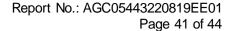


FRONT VIEW OF EUT



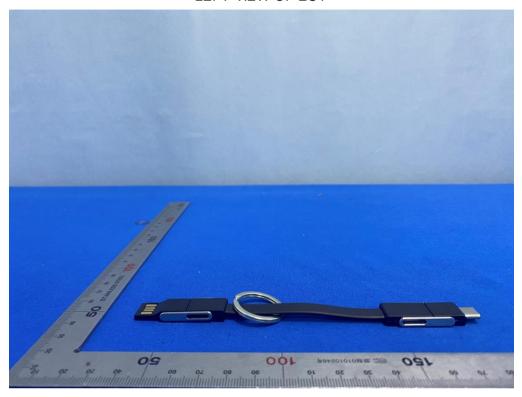
BACK VIEW OF EUT



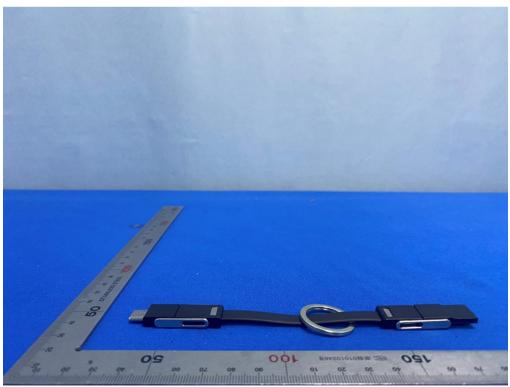


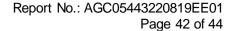


LEFT VIEW OF EUT



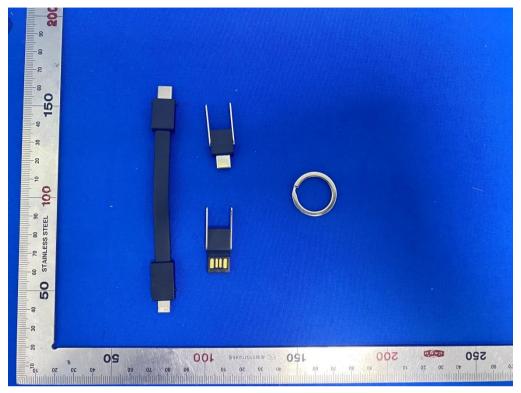
RIGHT VIEW OF EUT



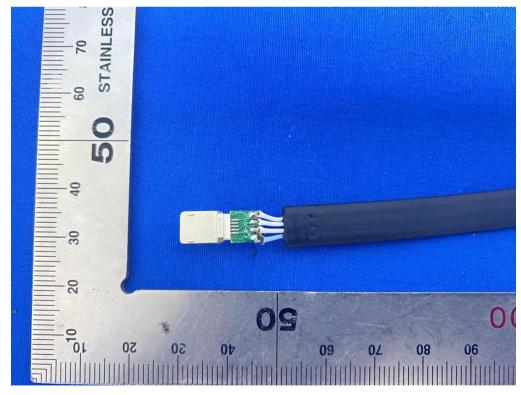


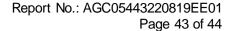


OPOEN VIEW OF EUT



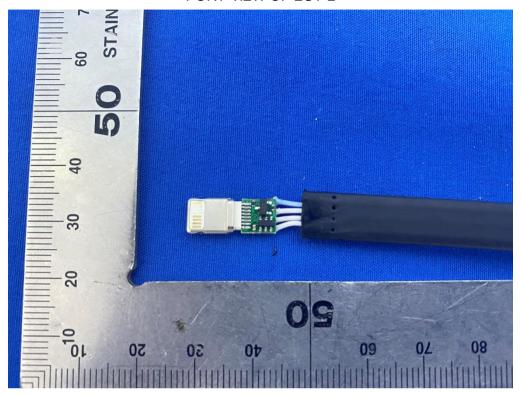
PORT VIEW OF EUT-1



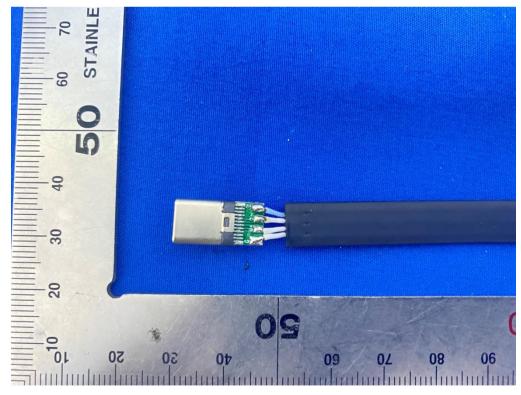




PORT VIEW OF EUT-2

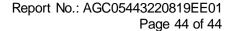


PORT VIEW OF EUT-3



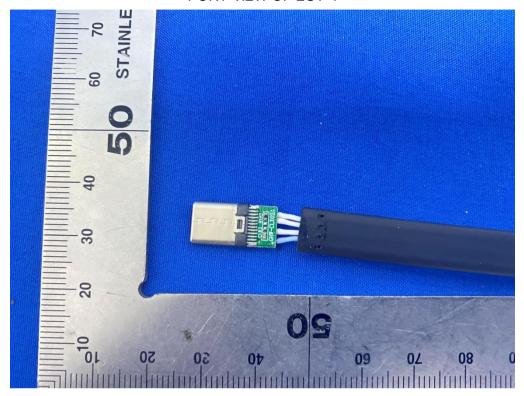
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PORT VIEW OF EUT-4



----END OF REPORT----



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- 3. The Company shall not be called or be liable to be called to give evidence or testimony on the Report in a court of law without its prior written consent, unless required by the relevant governmental authorities, laws or court orders.
- 4. In the event of the improper use of the report as determined by the Company, the Company reserves the right to withdraw it, and to adopt any other additional remedies which may be appropriate.
- 5. Samples submitted for testing are accepted on the understanding that the Report issued cannot form the basis of, or be the instrument for, any legal action against the Company.
- 6. The Company will not be liable for or accept responsibility for any loss or damage however arising from the use of information contained in any of its Reports or in any communication whatsoever about its said tests or investigations.
- 7. Clients wishing to use the Report in court proceedings or arbitration shall inform the Company to that effect prior to submitting the sample for testing.
- 8. The Company is not responsible for recalling the electronic version of the original report when any revision is made to them. The Client assumes the responsibility to providing the revised version to any interested party who uses them.
- 9. Subject to the variable length of retention time for test data and report stored hereinto as otherwise specifically required by individual accreditation authorities, the Company will only keep the supporting test data and information of the test report for a period of six years. The data and information will be disposed of after the aforementioned retention period has elapsed. Under no circumstances shall we provide any data and information which has been disposed of after retention period. Under no circumstances shall we be liable for damage of any kind, including (but not limited to) compensatory damages, lost profits, lost data, or any form of special, incidental, indirect, consequential or punitive damages of any kind, whether based on breach of contract of warranty, tort (including negligence), product liability or otherwise, even if we are informed in advance of the possibility of such damages.